



TMUX6219-Q1 ZHCSMY9C - JANUARY 2021 - REVISED DECEMBER 2024

TMUX6219-Q1 具有 1.8V 逻辑电平的汽车级 36V、低 Ron、2:1 (SPDT) 开关

1 特性

- 符合面向汽车应用的 AEC-Q100 标准 - 器件温度等级 1:-40℃ 至 125℃ 环境工作温 度范围
- 功能安全型
 - 可提供用于功能安全系统设计的文档
- 双电源电压范围: ±4.5V 至 ±18V
- 单电源电压范围: 4.5V 至 36V
- 低导通电阻:2.1Ω
- 低电荷注入:-10pC
- 大电流支持: 330mA (最大值) (VSSOP)
- 兼容 1.8V 逻辑电平
- 失效防护逻辑
- 轨到轨运行
- 双向信号路径
- 先断后合开关

2 应用

- 电动汽车充电站电源模块
- 高级驾驶辅助系统 (ADAS) ٠
- 汽车网关
- 模拟和数字多路复用/多路信号分离
- 汽车音响主机
- 远程信息处理控制单元
- 紧急呼叫 (eCall)
- 信息娱乐系统
- 车身控制模块 (BCM)
- 车身电子装置和照明
- 电池管理系统 (BMS)
- HVAC 控制器模块
- ADAS 域控制器

3 说明

TMUX6219-Q1 是一款的互补金属氧化物半导体 (CMOS)开关,采用单通道 2:1 (SPDT) 配置。此器件 在单电源(4.5V 至 36V)、双电源(±4.5V 至 ±18V) 或非对称电源 (例如 V_{DD} = 5V, V_{SS} = -8V)供电时均 能正常运行。TMUX6219-Q1 可在源极 (Sx) 和漏极 (D) 引脚上支持 V_{SS} 到 V_{DD} 范围的双向模拟和数字信 号。

可以通过控制 EN 引脚来使能或禁用 TMUX6219-Q1。 当禁用时,两个信号路径开关都被关闭。当启用时, SEL 引脚可用于打开信号路径 1 (S1 至 D) 或信号路 径 2 (S2 至 D)。所有逻辑控制输入均支持 1.8 V 到 Vnn 的逻辑电平,因此,当器件在有效电源电压范围内 运行时,可确保 TTL 和 CMOS 逻辑兼容性。失效防护 逻辑电路允许先在控制引脚上施加电压,然后在电源引 脚上施加电压,从而保护器件免受潜在的损害。

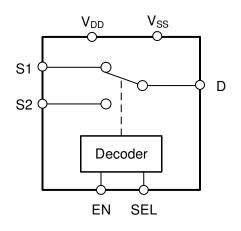
TMUX6219-Q1 属于精密开关和多路复用器器件系列。 这些器件具有非常低的导通和关断漏电流以及低电荷注 入,因此可用于高精度测量应用。

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器件型号	封装 ⁽¹⁾	封装尺寸 ⁽²⁾
TMUX6219-Q1	DGK (VSSOP, 8)	3mm × 4.9mm

有关更多信息,请参阅节11 (1)

封装尺寸(长×宽)为标称值,并包括引脚(如适用)。 (2)



TMUX6219-Q1 方框图





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4 Pin Configuration and Functions

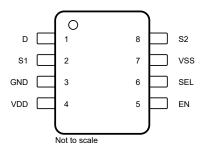


图 4-1. DGK Package, 8-Pin VSSOP (Top View)

表 4-1. Pin Functions

	PIN		DESCRIPTION (2)	
NAME	DGK		DESCRIPTION 4	
D	1	I/O	Drain pin. Can be an input or output.	
S1	2	I/O	Source pin 1. Can be an input or output.	
GND	3	Р	Ground (0V) reference	
V _{DD}	4	Р	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1μ F to 10μ F between V _{DD} and GND.	
EN	5	I	Active high logic enable, has internal pull-up resistor. When this pin is low, all switches are turn When this pin is high, the SEL logic input determine which switch is turned on.	
SEL	6	I	Logic control input, has internal pull-down resistor. Controls the switch connection as shown in † 7.5.	
V _{SS}	7	Р	Negative power supply. This pin is the most negative power-supply potential. In single-supply applications, this pin can be connected to ground. For reliable operation, connect a decoupling capacitor ranging from 0.1μ F to 10μ F between V _{SS} and GND.	
S2	8	I/O	Source pin 2. Can be an input or output.	
Thermal Pa	d	_	The thermal pad is not connected internally. It is recommended that the pad be tied to GND or VSS for best performance.	

(1) I = input, O = output, I/O = input and output, P = power.

(2) Refer to \ddagger 7.4 for what to do with unused pins.

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾ (2)

		MIN	MAX	UNIT
V _{DD} - V _{SS}			38	V
V _{DD}	Supply voltage	- 0.5	38	V
V _{SS}		- 38	0.5	V
V_{SEL} or V_{EN}	Logic control input pin voltage (SEL, EN) ⁽³⁾	- 0.5	38	V
I _{SEL} or I _{EN}	Logic control input pin current (SEL, EN) ⁽³⁾	- 30	30	mA
V_{S} or V_{D}	Source or drain voltage (Sx, D) ⁽³⁾	V _{SS} - 0.5	V _{DD} +0.5	V
I _{IK}	Diode clamp current ⁽³⁾	- 30	30	mA
I _S or I _{D (CONT)}	Source or drain continuous current (Sx, D)		I _{DC} + 10 % ⁽⁴⁾	mA
T _A	Ambient temperature	- 55	150	°C
T _{stg}	Storage temperature	- 65	150	°C
TJ	Junction temperature		150	°C
P _{tot}	Total power dissipation (DGK Package) ⁽⁵⁾		460	mW

(1) Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to ground, unless otherwise specified.

(3) Pins are diode-clamped to the power-supply rails. Over voltage signals must be voltage and current limited to maximum ratings.

(4) Refer to Source or Drain Continuous Current table for I_{DC} specifications.

(5) For DGK package: P_{tot} derates linearily above $T_A = 70^{\circ}C$ by 6.7mW/°C.

5.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/ JEDEC JS-001, all pins ⁽¹⁾	±2000	V
V _(ESD)		Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	±500	v

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

5.3 Thermal Information

		TMUX6219	
	THERMAL METRIC ⁽¹⁾	DGK (VSSOP)	UNIT
		8 PINS	
R _{0 JA}	Junction-to-ambient thermal resistance	152.1	°C/W
R _{0 JC(top)}	Junction-to-case (top) thermal resistance	48.4	°C/W
R _{0 JB}	Junction-to-board thermal resistance	73.2	°C/W
ΨJT	Junction-to-top characterization parameter	4.1	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	71.8	°C/W
R _{0 JC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



5.4 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
$V_{DD} - V_{SS}^{(1)}$	Power supply voltage differential	4.5	36	V
V _{DD}	Positive power supply voltage	4.5	36	V
V_S or V_D	Signal path input/output voltage (source or drain pin) (Sx, D)	V _{SS}	V _{DD}	V
V_{SEL} or V_{EN}	Address or enable pin voltage	0	36	V
I _S or I _{D (CONT)}	Source or drain continuous current (Sx, D)		I _{DC} ⁽²⁾	mA
T _A	Ambient temperature	- 40	125	°C

 V_{DD} and V_{SS} can be any value as long as 4.5 V \leqslant (V_{DD} $^-$ V_{SS}) \leqslant 36 V, and the minimum V_{DD} is met. Refer to *Source or Drain Continuous Current* table for I_{DC} specifications. (1)

(2)

5.5 Source or Drain Continuous Current

at supply voltage of $V_{DD} \pm 10\%$, $V_{SS} \pm 10\%$ (unless otherwise noted)

CONTIN	CONTINUOUS CURRENT PER CHANNEL (I _{DC})		T₄ = 85°C	T₄ = 125°C	UNIT
PACKAGE	TEST CONDITIONS	T _A = 25°C	14 - 05 C	1 _A - 123 C	ONT
	±15 V Dual Supply	330	210	120	mA
DGK (VSSOP)	+36 V Single Supply ⁽¹⁾	300	190	110	mA
	+12 V Single Supply	240	160	100	mA
	±5 V Dual Supply	240	160	100	mA
	+5 V Single Supply	180	120	80	mA

Specified for nominal supply voltage only. (1)



5.6 ±15 V Dual Supply: Electrical Characteristics

 $\label{eq:VDD} \begin{array}{l} V_{DD} = +15 \ V \pm 10\%, \ V_{SS} = -15 \ V \pm 10\%, \ GND = 0 \ V \ (unless \ otherwise \ noted) \\ Typical \ at \ V_{DD} = +15 \ V, \ V_{SS} = -15 \ V, \ T_A = 25 \ \ \ \ (unless \ otherwise \ noted) \end{array}$

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V _S = - 10 V to +10 V	25°C		2.1	2.9	Ω
R _{ON}	On-resistance	I _D = - 10 mA	- 40°C to +85°C			3.8	Ω
		Refer to On-Resistance	- 40°C to +125°C			4.5	Ω
		V _S = - 10 V to +10 V	25°C		0.05	0.25	Ω
ΔR_{ON}	On-resistance mismatch between channels	$I_{\rm D} = -10 {\rm mA}$	- 40°C to +85°C			0.3	Ω
		Refer to On-Resistance	- 40°C to +125°C			0.35	Ω
		V _S = - 10 V to +10 V	25°C		0.5	0.6	Ω
R _{ON FLAT}	On-resistance flatness	I _S = − 10 mA	- 40°C to +85°C			0.7	Ω
		Refer to On-Resistance	- 40°C to +125°C			0.85	Ω
R _{ON DRIFT}	On-resistance drift	V _S = 0 V, I _S = - 10 mA Refer to On-Resistance	- 40°C to +125°C		0.01		Ω/°C
		V _{DD} = 16.5 V, V _{SS} = - 16.5 V	25°C	- 0.2	0.05	0.2	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off V _S = +10 V / - 10 V	- 40°C to +85°C	- 1.6		1.6	nA
$V_{\rm D} = -10$	$V_D = -10 V / + 10 V$ Refer to Off-Leakage Current	- 40°C to +125°C	- 40		40	nA	
		V _{DD} = 16.5 V, V _{SS} = - 16.5 V	25°C	- 1	0.05	1	nA
1	Drain off leakage current ⁽¹⁾	Switch state is off V _S = +10 V / - 10 V	- 40°C to +85°C	- 3		3	nA
I _{D(OFF)}		$V_D = -10 V / + 10 V$ Refer to Off-Leakage Current	- 40°C to +125°C	- 60		60	nA
		V _{DD} = 16.5 V, V _{SS} = - 16.5 V	25°C	- 1	0.04	1	nA
I _{S(ON)}	Channel on leakage current ⁽²⁾	Switch state is on V _S = V _D = ±10 V	- 40°C to +85°C	- 2		2	nA
I _{D(ON)}		$v_{\rm S} = v_{\rm D} = \pm 10$ v Refer to On-Leakage Current	- 40°C to +125°C	- 50		50	nA
LOGIC IN	PUTS (SEL / EN pins)						
VIH	Logic voltage high		- 40°C to +125°C	1.3		36	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		0.8	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.005	2	μA
IIL	Input leakage current		- 40°C to +125°C	- 1	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF
POWER	SUPPLY		- 1				
			25°C		30	40	μA
DD	V _{DD} supply current	V_{DD} = 16.5 V, V_{SS} = - 16.5 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			48	μA
			- 40°C to +125°C			62	μA
			25°C		3	10	μA
I _{SS}	V _{SS} supply current	V_{DD} = 16.5 V, V_{SS} = - 16.5 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			15	μA
			- 40°C to +125°C			25	μA

(1) When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.

When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating. (2)



5.7 ±15 V Dual Supply: Switching Characteristics

 V_{DD} = +15 V ± 10%, V_{SS} = - 15 V ±10%, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +15 V, V_{SS} = - 15 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
		V _S = 10 V	25°C		120	175	ns
t _{TRAN}	Transition time from control input	$R_{L} = 300 \ \Omega$, $C_{L} = 35 \text{ pF}$	- 40°C to +85°C			190	ns
		Refer to Transition Time	- 40°C to +125°C			175	ns
		V _S = 10 V	25°C		100	170	ns
t _{ON (EN)}	Turn-on time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \text{ pF}$ Refer to Turn-on and Turn-off	- 40°C to +85°C			185	ns
		Time	- 40°C to +125°C			200	ns
		V _S = 10 V	25°C		100	180	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \text{ pF}$ Refer to Turn-on and Turn-off	- 40°C to +85°C			195	ns
		Time	- 40°C to +125°C			210	ns
		V _S = 10 V,	25°C		50		ns
t _{BBM}	Break-before-make time delay	$R_{L} = 300 \ \Omega$, $C_{L} = 35 \text{ pF}$	- 40°C to +85°C	1			ns
		Refer to Break-Before-Make	- 40°C to +125°C	1			ns
		V _{DD} rise time = 100 ns	25°C		0.19		ms
T _{ON (VDD)}	Device turn on time (V _{DD} to output)	$R_{L} = 300 \ \Omega$, $C_{L} = 35 \ pF$	- 40°C to +85°C		0.2		ms
		Refer to Turn-on (VDD) Time	- 40°C to +125°C		0.2		ms
t _{PD}	Propagation delay	$R_L = 50 \ \Omega$, $C_L = 5 \text{ pF}$ Refer to Propagation Delay	25°C		700		ps
Q _{INJ}	Charge injection	$V_D = 0 V, C_L = 1 nF$ Refer to Charge Injection	25°C		- 10		pC
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 0 V$, f = 100 kHz Refer to Off Isolation	25°C		- 75		dB
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 0 V$, $f = 1 MHz$ Refer to Off Isolation	25°C		- 55		dB
X _{TALK}	Crosstalk	$\begin{array}{l} R_{L} = 50 \ \Omega \ , C_{L} = 5 \ pF \\ V_{S} = 0 \ V, \ f = 100 \ kHz \\ Refer to \ Crosstalk \end{array}$	25°C		- 117		dB
X _{TALK}	Crosstalk	$\begin{array}{l} R_{L} = 50 \ \Omega \ , C_{L} = 5 \ pF \\ V_{S} = 0 \ V, \ f = 1MHz \\ Refer to \mathbf{Crosstalk} \end{array}$	25°C		- 106		dB
BW	- 3dB Bandwidth	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 0 V$ Refer to Bandwidth	25°C		40		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V _S = 0 V, f = 1 MHz	25°C		- 0.18		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R _L = 50 Ω , C _L = 5 pF, f = 1 MHz Refer to ACPSRR	25°C		- 64		dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP} = 15 \text{ V}, V_{BIAS} = 0 \text{ V}$ $R_{L} = 10 \text{ k} \Omega, C_{L} = 5 \text{ pF},$ f = 20 Hz to 20 KHz Refer to THD + Noise	25°C		0.0005		%
C _{S(OFF)}	Source off capacitance	V _S = 0 V, f = 1 MHz	25°C		33		pF
C _{D(OFF)}	Drain off capacitance	V _S = 0 V, f = 1 MHz	25°C		48		pF



$\label{eq:VDD} \begin{array}{l} V_{DD} = +15 \ V \pm 10\%, \ V_{SS} = \ - \ 15 \ V \pm 10\%, \ GND = 0 \ V \ (unless \ otherwise \ noted) \end{array}$

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
C _{S(ON)} , C _{D(ON)}	On capacitance	V _S = 0 V, f = 1 MHz	25°C		148		pF



5.8 36 V Single Supply: Electrical Characteristics

 V_{DD} = +36 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +36 V, V_{SS} = 0 V, T_A = 25 °C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT	
ANALOG	SWITCH					2.5 3.2 4.2 4.9 0.1 0.2 0.3 1 1.5 2 009 0.3 0.05 0.3 0.05 1 600 6.2 80 0.05 0.05 0.4 4.5 70 36 0.8 005 2		
		V _S = 0 V to 30 V	25°C		2.5	3.2	Ω	
R _{ON}	On-resistance	$I_{\rm D} = -10 {\rm mA}$	- 40°C to +85°C			4.2	Ω	
		Refer to On-Resistance	- 40°C to +125°C			4.9	Ω	
		$V_{\rm S} = 0$ V to 30 V	25°C		0.1	0.2	Ω	
ΔR_{ON}	On-resistance mismatch between channels	$I_{\rm D} = -10 {\rm mA}$	- 40°C to +85°C			0.25	Ω	
		Refer to On-Resistance	- 40°C to +125°C			0.3	Ω	
		V _S = 0 V to 30 V	25°C		0.3	1	Ω	
R _{ON FLAT}	On-resistance flatness	I _S = - 10 mA	- 40°C to +85°C			1.5	Ω	
		Refer to On-Resistance	- 40°C to +125°C			2	Ω	
R _{ON DRIFT}	On-resistance drift	V _S = 18 V, I _S = - 10 mA Refer to On-Resistance	- 40°C to +125°C		0.009		Ω/°C	
		V _{DD} = 39.6 V, V _{SS} = 0 V	25°C	- 0.3	0.05	0.3	nA	
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off V _S = 30 V / 1 V	- 40°C to +85°C	- 3.5		3.5	nA	
0(011)	5	V _D = 1 V / 30 V Refer to Off-Leakage Current	- 40°C to +125°C	- 60	0 60	nA		
		V _{DD} = 39.6 V, V _{SS} = 0 V	25°C	- 1	0.05	1	nA	
I _{D(OFF)}	Drain off leakage current ⁽¹⁾	Switch state is off $V_S = 30 V / 1 V$	- 40°C to +85°C	- 6.2		6.2	nA	
		$V_{D} = 1 V / 30 V$ Refer to Off-Leakage Current	- 40°C to +125°C	- 80		3.2 4.2 4.9 0.2 0.25 0.3 1 1.5 2 0.3 3.5 60 1 60 1 6.2 80 0.4 4.5 70 36 0.4 4.5 70 36 0.8 2 36 0.8 2 50 58	nA	
		V _{DD} = 39.6 V, V _{SS} = 0 V	25°C	- 0.4	0.05	0.4	nA	
I _{S(ON)} I _{D(ON)}	Channel on leakage current ⁽²⁾	Switch state is on V _S = V _D = 30 V or 1 V	- 40°C to +85°C	- 4.5		4.5	nA	
·D(ON)		Refer to On-Leakage Current	- 40°C to +125°C	- 70		70	nA	
LOGIC IN	PUTS (SEL / EN pins)							
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		36	V	
V _{IL}	Logic voltage low		- 40°C to +125°C	0		0.8	V	
I _{IH}	Input leakage current		- 40°C to +125°C		0.005	2	μA	
IIL	Input leakage current		- 40°C to +125°C	- 1	- 0.005		μA	
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF	
POWER S	SUPPLY	1						
			25°C		28	50	μA	
I _{DD}	V _{DD} supply current	V_{DD} = 39.6 V, V_{SS} = 0 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			58	μA	
			- 40°C to +125°C			70	μA	

(1) When V_S is 30 V, V_D is 1 V, or when V_S is 1 V, V_D is 30 V.

(2) When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.



5.9 36 V Single Supply: Switching Characteristics

 V_{DD} = +36 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +36 V, V_{SS} = 0 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
		V _S = 18 V	25°C		110	170	ns
t _{TRAN}	Transition time from control input	$R_{L} = 300 \ \Omega$, $C_{L} = 35 \text{ pF}$	- 40°C to +85°C			185	ns
		Refer to Transition Time	- 40°C to +125°C			200	ns
		V _S = 18 V	25°C		110	180	ns
t _{ON (EN)}	Turn-on time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \text{ pF}$ Refer to Turn-on and Turn-off	- 40°C to +85°C			190	ns
		Time	- 40°C to +125°C			200	ns
		V _S = 18 V	25°C		90	180	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \text{ pF}$ Refer to Turn-on and Turn-off	- 40°C to +85°C			195	ns
		Time	- 40°C to +125°C			200	ns
		V _S = 18 V,	25°C		44		ns
t _{BBM}	Break-before-make time delay	$R_{L} = 300 \ \Omega$, $C_{L} = 35 \text{ pF}$	- 40°C to +85°C	1			ns
		Refer to Break-Before-Make	- 40°C to +125°C	1			ns
		V _{DD} rise time = 100 ns	25°C		0.17		ms
T _{ON (VDD)}	Device turn on time (V _{DD} to output)	$R_L = 300 \ \Omega$, $C_L = 35 \ pF$	- 40°C to +85°C		0.19		ms
		Refer to Turn-on (VDD) Time	- 40°C to +125°C		0.19		ms
t _{PD}	Propagation delay	$R_L = 50 \ \Omega$, $C_L = 5 \ pF$ Refer to Propagation Delay	25°C		920		ps
Q _{INJ}	Charge injection	V _D = 18 V, C _L = 1 nF Refer to Charge Injection	25°C		- 13		рС
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 100 kHz$ Refer to Off Isolation	25°C		- 75		dB
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 1 MHz$ Refer to Off Isolation	25°C		- 55		dB
X _{TALK}	Crosstalk	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 100 kHz$ Refer to Crosstalk	25°C		- 117		dB
X _{TALK}	Crosstalk	$\begin{array}{l} R_{L} = 50 \ \Omega \ , C_{L} = 5 \ pF \\ V_{S} = 6 \ V, \ f = 1MHz \\ Refer to Crosstalk \end{array}$	25°C		- 106		dB
BW	- 3dB Bandwidth	$R_L = 50 \ \Omega$, $C_L = 5 \ pF$ $V_S = 6 \ V$, Refer to Bandwidth	25°C		38		MHz
IL	Insertion loss	$R_L = 50 \ \Omega$, $C_L = 5 \ pF$ $V_S = 6 \ V$, $f = 1 \ MHz$	25°C		- 0.19		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R _L = 50 Ω , C _L = 5 pF, f = 1 MHz Refer to ACPSRR	25°C		- 60		dB
THD+N	Total Harmonic Distortion + Noise	$\label{eq:VPP} \begin{array}{l} V_{PP} = 18 \ V, \ V_{BIAS} = 18 \ V \\ R_{L} = 10 \ k^{\Omega} \ , \ C_{L} = 5 \ pF, \\ f = 20 \ Hz \ to \ 20 \ HHz \\ Refer \ to \ THD \ + \ Noise \end{array}$	25°C		0.0004		%
C _{S(OFF)}	Source off capacitance	V _S = 6 V, f = 1 MHz	25°C		35		pF
C _{D(OFF)}	Drain off capacitance	V _S = 6 V, f = 1 MHz	25°C		49		pF



 V_{DD} = +36 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +36 V, V_{SS} = 0 V, T_A = 25 °C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
C _{S(ON),} C _{D(ON)}	On capacitance	V _S = 6 V, f = 1 MHz	25°C		146		pF



5.10 12 V Single Supply: Electrical Characteristics

 V_{DD} = +12 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +12 V, V_{SS} = 0 V, T_A = 25 °C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		$V_{\rm S} = 0 \text{V}$ to 10 V	25°C		4.6	6	Ω
R _{ON}	On-resistance	$I_{\rm D} = -10 {\rm mA}$	- 40°C to +85°C			7.5	Ω
		Refer to On-Resistance	- 40°C to +125°C			8.4	Ω
		V _S = 0 V to 10 V	25°C		0.08	0.2	Ω
ΔR_{ON}	On-resistance mismatch between channels	I _D = - 10 mA	- 40°C to +85°C			0.32	Ω
		Refer to On-Resistance	- 40°C to +125°C			0.35	Ω
		V _S = 0 V to 10 V	25°C		1.2	2	Ω
R _{ON FLAT}	On-resistance flatness	I _S = - 10 mA	- 40°C to +85°C			2.2	Ω
		Refer to On-Resistance	- 40°C to +125°C			2.4	Ω
R _{ON DRIFT}	On-resistance drift	V _S = 6 V, I _S = - 10 mA Refer to On-Resistance	- 40°C to +125°C		0.017		Ω/°C
		V _{DD} = 13.2 V, V _{SS} = 0 V	25°C	- 0.5	0.05	0.5	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off $V_S = 10 V / 1 V$	- 40°C to +85°C	- 2		2	nA
-3(011)		$V_D = 1 V / 10 V$ Refer to Off-Leakage Current		30	nA		
		V _{DD} = 13.2 V, V _{SS} = 0 V	25°C	- 0.5	0.05	0.5	nA
I _{D(OFF)}	Drain off leakage current ⁽¹⁾	Switch state is off V _S = 10 V / 1 V	- 40°C to +85°C	- 3		3	nA
5(011)		$V_{D} = 1 \text{ V} / 10 \text{ V}$ Refer to Off-Leakage Current	- 40°C to +125°C	- 50		6 7.5 8.4 0.2 0.32 0.35 2 2.2 2.4 0.5 2 30 0.5	nA
		V _{DD} = 13.2 V, V _{SS} = 0 V	25°C	- 1.5	0.05	1.5	nA
I _{S(ON)} I _{D(ON)}	Channel on leakage current ⁽²⁾	Switch state is on $V_S = V_D = 10 V \text{ or } 1 V$	- 40°C to +85°C	- 3		3	nA
D(OIV)		Refer to On-Leakage Current	- 40°C to +125°C	- 40		40	nA
LOGIC IN	PUTS (SEL / EN pins)						
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		36	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		0.8	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.005	2	μA
IIL	Input leakage current		- 40°C to +125°C	- 1	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF
POWER S	SUPPLY	•					
			25°C		10	35	μA
I _{DD}	V _{DD} supply current	V_{DD} = 13.2 V, V_{SS} = 0 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			45	μA
			- 40°C to +125°C			55	μA

(1) When V_S is 10 V, V_D is 1 V, or when V_S is 1 V, V_D is 10 V.

(2) When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.



5.11 12 V Single Supply: Switching Characteristics

 V_{DD} = +12 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +12 V, V_{SS} = 0 V, T_A = 25 °C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
		V _S = 8 V	25°C		180	185	ns
t _{TRAN}	Transition time from control input	$R_{L} = 300 \ \Omega$, $C_{L} = 35 \ pF$	- 40°C to +85°C			215	ns
		Refer to Transition Time	- 40°C to +125°C			235	ns
		V _S = 8 V	25°C		120	180	ns
t _{ON (EN)}	Turn-on time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \text{ pF}$ Refer to Turn-on and Turn-off	- 40°C to +85°C			210	ns
. ,		Time	- 40°C to +125°C			230	ns
		V _S = 8 V	25°C		130	210	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \text{ pF}$ Refer to Turn-on and Turn-off	- 40°C to +85°C			235	ns
		Time	- 40°C to +125°C			250	ns
		V _S = 8 V,	25°C		40		ns
t _{BBM}	Break-before-make time delay	R _L = 300 Ω, C _L = 35 pF	- 40°C to +85°C	1			ns
		Refer to Break-Before-Make	- 40°C to +125°C	1			ns
		V _{DD} rise time = 100 ns	25°C		0.19		ms
T _{ON (VDD)}	Device turn on time (V _{DD} to output)	$R_L = 300 \ \Omega$, $C_L = 35 \text{ pF}$	- 40°C to +85°C		0.2		ms
		Refer to Turn-on (VDD) Time	- 40°C to +125°C		0.2		ms
t _{PD}	Propagation delay	$R_L = 50 \ \Omega$, $C_L = 5 \text{ pF}$ Refer to Propagation Delay	25°C		740		ps
Q _{INJ}	Charge injection	$V_D = 6 V, C_L = 1 nF$ Refer to Charge Injection	25°C		- 6		pC
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 100 kHz$ Refer to Off Isolation	25°C		- 75		dB
O _{ISO}	Off-isolation	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 1 MHz$ Refer to Off Isolation	25°C		- 55		dB
X _{TALK}	Crosstalk	$R_L = 50 \ \Omega$, $C_L = 5 \text{ pF}$ $V_S = 6 \text{ V, } f = 100 \text{ kHz}$ Refer to Crosstalk	25°C		- 117		dB
X _{TALK}	Crosstalk	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$, $f = 1 MHz$ Refer to Crosstalk	25°C		- 106		dB
BW	- 3dB Bandwidth	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 6 V$ Refer to Bandwidth	25°C		42		MHz
IL	Insertion loss	$R_L = 50 Ω$, $C_L = 5 pF$ V _S = 6 V, f = 1 MHz	25°C		- 0.3		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R _L = 50 Ω , C _L = 5 pF, f = 1 MHz Refer to ACPSRR	25°C		- 65		dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP} = 6 V, V_{BIAS} = 6 V$ $R_{L} = 10 k \Omega, C_{L} = 5 pF,$ f = 20 Hz to 20 kHz Refer to THD + Noise	25°C		0.0009		%
C _{S(OFF)}	Source off capacitance	V _S = 6 V, f = 1 MHz	25°C		38		pF
C _{D(OFF)}	Drain off capacitance	V _S = 6 V, f = 1 MHz	25°C		56		pF



 V_{DD} = +12 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +12 V, V_{SS} = 0 V, T_A = 25 °C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
C _{S(ON)} , C _{D(ON)}	On capacitance	V _S = 6 V, f = 1 MHz	25°C		150		pF



5.12 +5 V / -8 V Dual Supply: Electrical Characteristics

 V_{DD} = +5 V ± 10%, V_{SS} = -8 V ±10%, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +5 V, V_{SS} = -5 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V _{DD} = +5 V, V _{SS} = -8 V	25°C		4.2	5.5	Ω
R _{ON}	On-resistance	$V_{S} = V_{DD}$ to V_{SS}	- 40°C to +85°C			6.8	Ω
		I _D = - 10 mA Refer to On-Resistance	- 40°C to +125°C			7.6	Ω
			25°C		0.1	0.23	Ω
ΔR_{ON}	On-resistance mismatch between channels	$V_{S} = V_{DD}$ to V_{SS} $I_{D} = -10 \text{ mA}$	- 40°C to +85°C			0.27	Ω
		Refer to On-Resistance	- 40°C to +125°C			0.35	Ω
		$\lambda (z = \lambda (z = to) / z$	25°C		1	1.5	Ω
R _{ON FLAT}	On-resistance flatness	$V_{\rm S} = V_{\rm DD}$ to $V_{\rm SS}$ $I_{\rm D} = -10$ mA	- 40°C to +85°C			1.7	Ω
		Refer to On-Resistance	- 40°C to +125°C			2	Ω
R _{ON DRIFT}	On-resistance drift	$V_S = 0 V$, $I_S = -10 mA$ Refer to On-Resistance	- 40°C to +125°C		0.019		Ω/°C
		V _{DD} = +5.5 V, V _{SS} = -8.8 V	25°C	- 0.3	0.1	0.3	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off $V_S = V_{DD} - 1 / V_{SS} + 1$	- 40°C to +85°C	- 3		3	nA
·3(0FF)		$V_D = V_{SS} + 1 / V_{DD} - 1$ Refer to Off-Leakage Current	- 40°C to +125°C	- 50		50	nA
		V _{DD} = +5.5 V, V _{SS} = -8.8 V	25°C	- 0.5	0.1	0.5	nA
I _{D(OFF)}	Drain off leakage current ⁽¹⁾	Switch state is off $V_{S} = V_{DD} - 1 / V_{SS} + 1$	- 40°C to +85°C	- 3		3	nA
5(011)		$V_D = V_{SS} + 1 / V_{DD} - 1$ Refer to Off-Leakage Current	- 40°C to +125°C	- 55		6.8 7.6 0.23 0.27 0.35 1.5 1.7 2 0.3 3 3 50 0.5 3 3 55 0.5 3 3 40 44 44 0.8 2 44 0.8 2 30 37 42 55 8	nA
		V_{DD} = +5.5 V, V_{SS} = -8.8 V	25°C	- 0.5	0.1	0.5	nA
I _{S(ON)} I _{D(ON)}	Channel on leakage current ⁽²⁾	Switch state is on $V_{S} = V_{D} = V_{DD} - 1 / V_{SS} + 1$	- 40°C to +85°C	- 3		3	nA
D(ON)		Refer to On-Leakage Current	- 40°C to +125°C	- 40		40	nA
LOGIC INF	PUTS (SEL / EN pins)						
VIH	Logic voltage high		- 40°C to +125°C	1.3		44	V
VIL	Logic voltage low		- 40°C to +125°C	0		0.8	V
IIH	Input leakage current		- 40°C to +125°C		0.005	2	μA
IIL	Input leakage current		- 40°C to +125°C	- 1	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF
POWER S	UPPLY					I	
			25°C		24	30	μA
I _{DD}	V _{DD} supply current	V_{DD} = +5.5 V, V_{SS} = -8.8 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			37	μA
			- 40°C to +125°C			42	μA
			25°C		1	5	μA
I _{SS}	V _{SS} supply current	V_{DD} = +5.5 V, V_{SS} = -8.8 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			8	μA
			- 40°C to +125°C			12	μA

(1) When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.

(2) When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.



5.13 +5 V / -8 V Dual Supply: Switching Characteristics

 $V_{DD} = +5 \text{ V} \pm 10\%, V_{SS} = -5 \text{ V} \pm 10\%, \text{ GND} = 0 \text{ V} \text{ (unless otherwise noted)}$ Typical at $V_{DD} = +5 \text{ V}, V_{SS} = -5 \text{ V}, T_A = 25^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	TA	MIN	TYP	MAX	UNIT
		V _S = 3 V	25°C		180	190	ns
TRAN	Transition time from control input	$R_{L} = 300 \ \Omega$, $C_{L} = 35 \text{ pF}$	- 40°C to +85°C			220	ns
		Refer to Transition Time	- 40°C to +125°C			240	ns
		V _S = 3 V	25°C		120	180	ns
t _{ON (EN)}	Turn-on time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \ pF$	- 40°C to +85°C			215	ns
		Refer to Turn-on and Turn-off Time	- 40°C to +125°C			240	ns
		V _S = 3 V	25°C		130	220	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \Omega$, $C_L = 35 pF$	- 40°C to +85°C			245	ns
		Refer to Turn-on and Turn-off Time	- 40°C to +125°C			270	ns
		V _S = 3 V,	25°C		60		ns
t _{ввм}	Break-before-make time delay	R _L = 300 Ω, C _L = 35 pF	- 40°C to +85°C	1			ns
		Refer to Break-Before-Make	- 40°C to +125°C	1			ns
		V _{DD} rise time = 1us	25°C		0.19		ms
T _{ON (VDD)}	Device turn on time (V _{DD} to output)	R _L = 300 Ω, C _L = 35pF	- 40°C to +85°C		0.19	1	ms
	(100	Refer to Turn-on (VDD) Time	- 40°C to +125°C		0.19	1	ms
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$ Refer to Propagation Delay	25°C		650		ps
Q _{INJ}	Charge injection	$V_D = 0 V, C_L = 1 nF$ Refer to Charge Injection	25°C		14		рС
O _{ISO}	Off-isolation	$ \begin{array}{l} R_{L} = 50 \ \Omega \ , \ C_{L} = 5 \ pF \\ V_{S} = 0 \ V, \ f = 100 \ kHz \\ Refer to \ Off \ Isolation \end{array} $	25°C		- 75		dB
O _{ISO}	Off-isolation	$ \begin{array}{l} R_{L} = 50 \ \Omega \ , \ C_{L} = 5 \ pF \\ V_{S} = 0 \ V, \ f = 1 \ MHz \\ Refer to \ Off \ Isolation \end{array} $	25°C		- 55		dB
X _{TALK}	Crosstalk	$ \begin{array}{l} R_{L} = 50 \ \Omega \ , \ C_{L} = 5 \ pF \\ V_{S} = 0 \ V, \ f = 100 \ kHz \\ Refer to Crosstalk \end{array} $	25°C		- 80		dB
X _{TALK}	Crosstalk	$ \begin{array}{l} R_{L} = 50 \ \Omega \ , \ C_{L} = 5 \ pF \\ V_{S} = 0 \ V, \ f = 1 MHz \\ Refer to Crosstalk \end{array} $	25°C		- 70		dB
BW	- 3dB Bandwidth	$R_L = 50 \Omega$, $C_L = 5 pF$ $V_S = 0 V$, Refer to Bandwidth	25°C		42		MHz
IL	Insertion loss	R_{L} = 50 Ω , C_{L} = 5 pF V_{S} = 0 V, f = 1 MHz	25°C		- 0.3		dB
ACPSRR	AC Power Supply Rejection Ratio	$\label{eq:VP} \begin{array}{l} V_{PP} = 0.62 \ V \ \text{on} \ V_{DD} \ \text{and} \ V_{SS} \\ R_L = 50 \ \Omega \ , \ C_L = 5 \ \text{pF}, \\ f = 1 \ \text{MHz} \\ \text{Refer to} \ \text{ACPSRR} \end{array}$	25°C		- 68		dB
THD+N	Total Harmonic Distortion + Noise	$\label{eq:VPP} \begin{array}{l} V_{PP} = 5 \ V, \ V_{BIAS} = 0 \ V \\ R_{L} = 10 \ k \ \Omega \ , \ C_{L} = 5 \ pF, \\ f = 20 \ Hz \ to \ 20 \ kHz \\ Refer \ to \ THD \ + \ Noise \end{array}$	25°C		0.001		%
C _{S(OFF)}	Source off capacitance	V _S = 0 V, f = 1 MHz	25°C		36		pF
C _{D(OFF)}	Drain off capacitance	V _S = 0 V, f = 1 MHz	25°C		53		pF
C _{S(ON),} C _{D(ON)}	On capacitance	V _S = 0 V, f = 1 MHz	25°C		142		pF



5.14 ±5 V Dual Supply: Electrical Characteristics

 $\label{eq:VDD} \begin{array}{l} V_{DD} = +5 \ V \pm 10\%, \ V_{SS} = \ -5 \ V \pm 10\%, \ GND = 0 \ V \ (unless \ otherwise \ noted) \\ Typical \ at \ V_{DD} = +5 \ V, \ V_{SS} = \ -5 \ V, \ T_A = 25 \ ^{\circ} \! \mathbb{C} \ \ (unless \ otherwise \ noted) \end{array}$

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
		V _{DD} = +4.5 V, V _{SS} = -4.5 V	25°C		4	7.2	Ω
R _{ON}	On-resistance	$V_{\rm S} = -4.5 \text{V}$ to +4.5 V	- 40°C to +85°C			8.6	Ω
		I _D = - 10 mA Refer to On-Resistance	- 40°C to +125°C			10	Ω
		V _S = -4.5 V to +4.5 V	25°C		0.1	0.3	Ω
ΔR_{ON}	On-resistance mismatch between channels	$I_{\rm D} = -10 \text{mA}$	- 40°C to +85°C			0.35	Ω
		Refer to On-Resistance	- 40°C to +125°C			0.4	Ω
		$V_{\rm S} = -4.5$ V to +4.5 V	25°C		1.3	2.2	Ω
R _{ON FLAT}	On-resistance flatness	$I_{\rm D} = -10 \rm{mA}$	- 40°C to +85°C			2.5	Ω
		Refer to On-Resistance	- 40°C to +125°C			2.8	Ω
R _{ON DRIFT}	On-resistance drift	V _S = 0 V, I _S = - 10 mA Refer to On-Resistance	- 40°C to +125°C		0.019		Ω/°C
		V_{DD} = +5.5 V, V_{SS} = -5.5 V	25°C	- 0.3	0.05	0.3	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off V _S = +4.5 V / - 4.5 V	- 40°C to +85°C	- 1		1	nA
'S(UFF)		$V_D = -4.5 V / +4.5 V$ Refer to Off-Leakage Current	- 40°C to +125°C	- 30		30	nA
		V _{DD} = +5.5 V, V _{SS} = -5.5 V	25°C	- 0.4	0.05	0.4	nA
	Drain off leakage current ⁽¹⁾	Switch state is off V _S = +4.5 V / - 4.5 V	- 40°C to +85°C	- 3		3	nA
I _{D(OFF)}		$V_D = -4.5 V / +4.5 V$ Refer to Off-Leakage Current	- 40°C to +125°C	- 50		8.6 10 0.3 0.35 0.4 2.2 2.5 2.8 0.3 1 30 0.4 3 0.4 3 0.4 3 0.4 3 0.4 3 0.4 3 0.4 3 0.4 3 0.4 3 0.4 3 0.4 3 0.4 3 0.3 50 0.4 50 0.4 50 55 8	nA
		V _{DD} = +5.5 V, V _{SS} = - 5.5 V	25°C	- 0.4	0.05	0.4	nA
I _{S(ON)}	Channel on leakage current ⁽²⁾	Switch state is on $V_S = V_D = \pm 4.5 V$	- 40°C to +85°C	- 3		3	nA
I _{D(ON)}		Refer to On-Leakage Current	- 40°C to +125°C	- 40		40	nA
LOGIC IN	PUTS (SEL / EN pins)						
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		36	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		0.8	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.005	2	μA
IIL	Input leakage current		- 40°C to +125°C	- 1	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3		pF
POWER	SUPPLY						
			25°C		20	35	μA
I _{DD}	V _{DD} supply current	V_{DD} = +5.5 V, V_{SS} = -5.5 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			40	μA
			- 40°C to +125°C			50	μA
			25°C		0.001	5	μA
I _{SS}	V _{SS} supply current	V_{DD} = +5.5 V, V_{SS} = -5.5 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			8	μA
			- 40°C to +125°C			15	μA

When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive. (1)

(2) When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.



5.15 ±5 V Dual Supply: Switching Characteristics

 $V_{DD} = +5 \text{ V} \pm 10\%, V_{SS} = -5 \text{ V} \pm 10\%, \text{ GND} = 0 \text{ V} \text{ (unless otherwise noted)}$ Typical at $V_{DD} = +5 \text{ V}, V_{SS} = -5 \text{ V}, T_A = 25^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
		V _S = 3 V	25°C		300	400	ns
t _{TRAN}	Transition time from control input	$R_{L} = 300 \ \Omega$, $C_{L} = 35 \ pF$	- 40°C to +85°C			490	ns
		Refer to Transition Time	- 40°C to +125°C			550	ns
		V _S = 3 V	25°C		220	300	ns
t _{ON (EN)}	Turn-on time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \text{ pF}$ Refer to Turn-on and Turn-off	- 40°C to +85°C			350	ns
		Time	- 40°C to +125°C			380	ns
		V _S = 3 V	25°C		210	280	ns
t _{OFF (EN)}	Turn-off time from enable	$R_L = 300 \ \Omega$, $C_L = 35 \text{ pF}$ Refer to Turn-on and Turn-off	- 40°C to +85°C			330	ns
		Time	- 40°C to +125°C			350	ns
		V _S = 3 V,	25°C		50		ns
t _{BBM}	Break-before-make time delay	$R_{L} = 300 \ \Omega$, $C_{L} = 35 \ pF$	- 40°C to +85°C	1			ns
		Refer to Break-Before-Make	- 40°C to +125°C	1			ns
		V _{DD} rise time = 100 ns	25°C		0.19		ms
T _{ON (VDD)}	Device turn on time (V _{DD} to output)	$R_{L} = 300 \ \Omega$, $C_{L} = 35 pF$	- 40°C to +85°C		0.19	1	ms
		Refer to Turn-on (VDD) Time	- 40°C to +125°C		0.19	1	ms
t _{PD}	Propagation delay	$R_L = 50 \ \Omega$, $C_L = 5 \text{ pF}$ Refer to Propagation Delay	25°C		650		ps
Q _{INJ}	Charge injection	$V_D = 0 V, C_L = 1 nF$ Refer to Charge Injection	25°C		- 5		рС
O _{ISO}	Off-isolation	$R_L = 50 \ \Omega$, $C_L = 5 \ pF$ $V_S = 0 \ V$, f = 100 kHz Refer to Off Isolation	25°C		- 75		dB
O _{ISO}	Off-isolation	$R_L = 50 \ \Omega$, $C_L = 5 \ pF$ $V_S = 0 \ V$, f = 1 MHz Refer to Off Isolation	25°C		- 55		dB
X _{TALK}	Crosstalk	$\begin{array}{l} R_{L} = 50 \ \ \Omega \ , \ C_{L} = 5 \ pF \\ V_{S} = 0 \ V, \ f = 100 \ kHz \\ Refer to Crosstalk \end{array}$	25°C		- 117		dB
X _{TALK}	Crosstalk	$R_L = 50 \ \Omega$, $C_L = 5 \ pF$ $V_S = 0 \ V$, $f = 1 \ MHz$ Refer to Crosstalk	25°C		- 106		dB
BW	- 3dB Bandwidth	$R_L = 50 \ \Omega$, $C_L = 5 \ pF$ $V_S = 0 \ V$, Refer to Bandwidth	25°C		43		MHz
IL	Insertion loss	$R_L = 50 \ \Omega$, $C_L = 5 \ pF$ $V_S = 0 \ V$, $f = 1 \ MHz$	25°C		- 0.35		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R _L = 50 Ω , C _L = 5 pF, f = 1 MHz Refer to ACPSRR	25°C		- 68		dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP} = 5 V, V_{BIAS} = 0 V$ $R_{L} = 10 k \Omega, C_{L} = 5 pF,$ f = 20 Hz to 20 kHz Refer to THD + Noise	25°C		0.001		%
C _{S(OFF)}	Source off capacitance	V _S = 0 V, f = 1 MHz	25°C		40		pF
C _{D(OFF)}	Drain off capacitance	V _S = 0 V, f = 1 MHz	25°C		60		pF



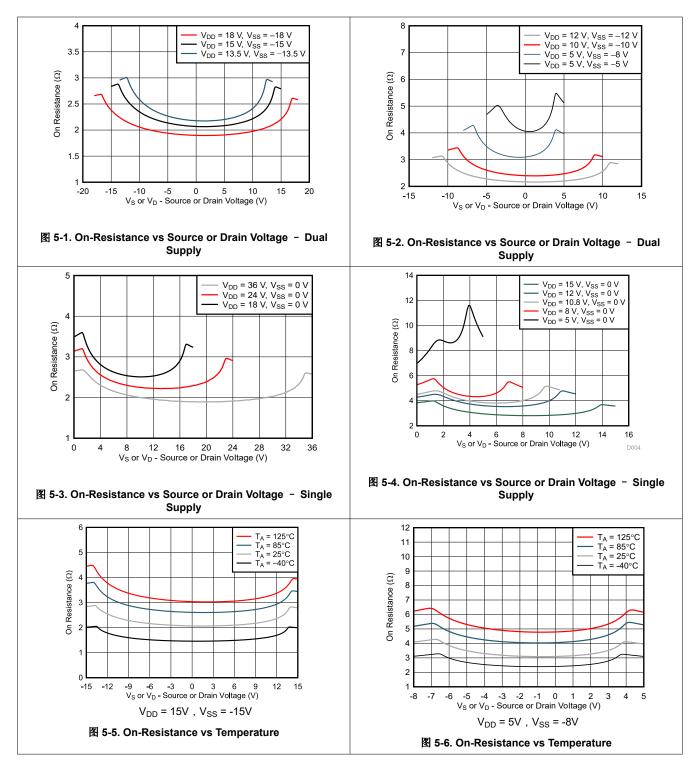
 V_{DD} = +5 V ± 10%, V_{SS} = -5 V ±10%, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +5 V, V_{SS} = -5 V, T_A = 25°C (unless otherwise noted)

Typical at	$v_{DD} = +3 v, v_{SS} = -3 v, T_A = 2$	25 C (unless otherwise noted)				
	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP MA	VINIT
C _{S(ON),} C _{D(ON)}	On capacitance	V _S = 0 V, f = 1 MHz	25°C		150	pF



5.16 Typical Characteristics

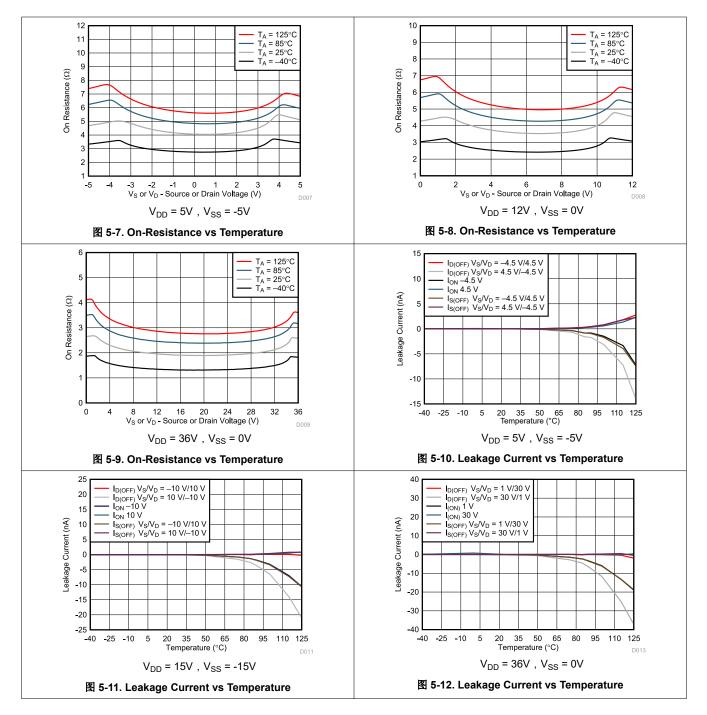
at T_A = 25°C



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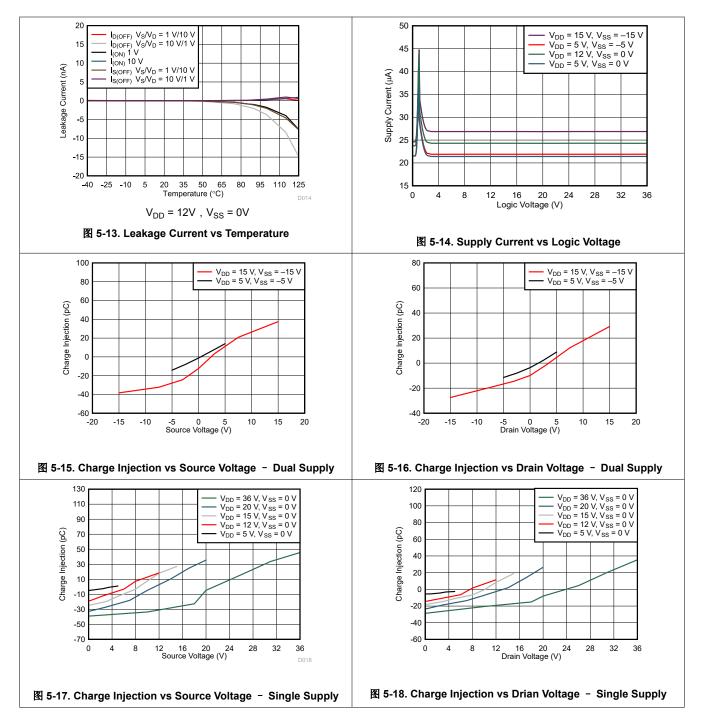


at $T_A = 25^{\circ}C$





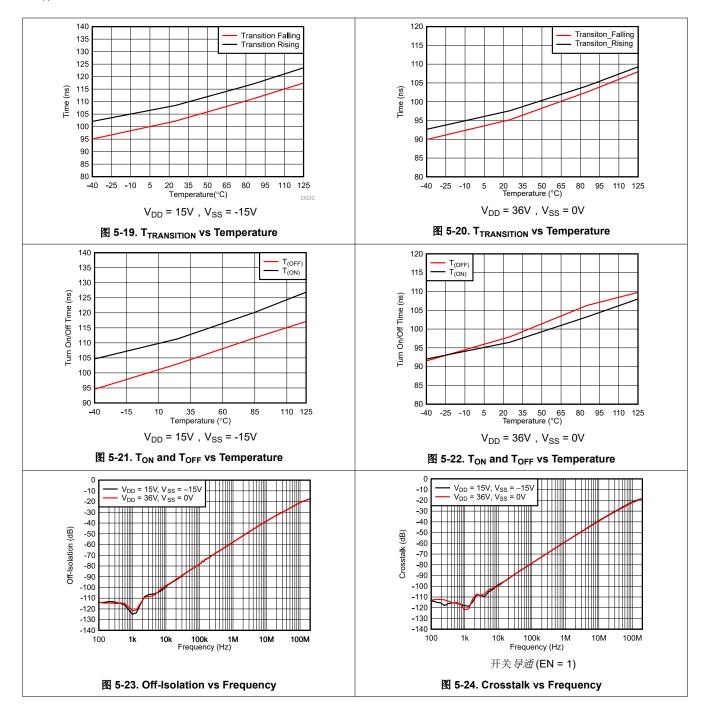
at T_A = 25°C



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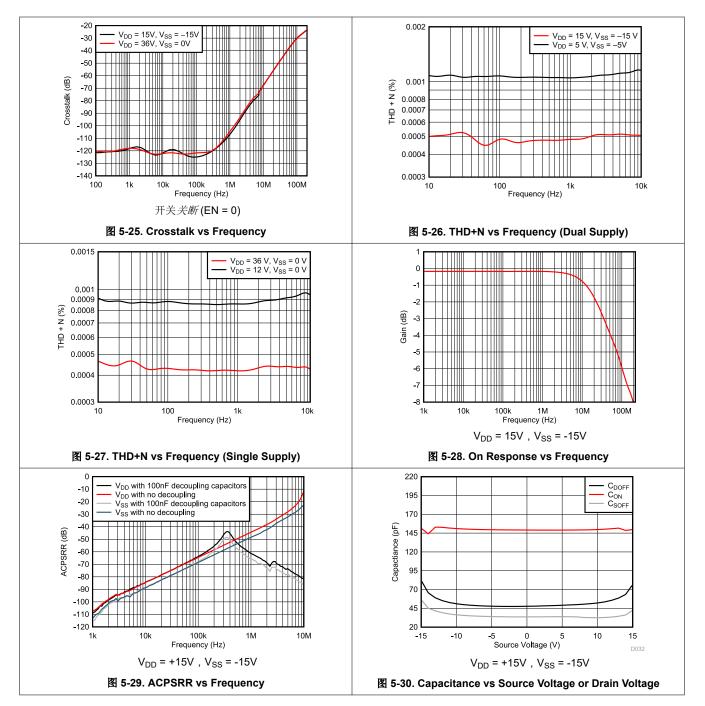


at T_A = 25°C



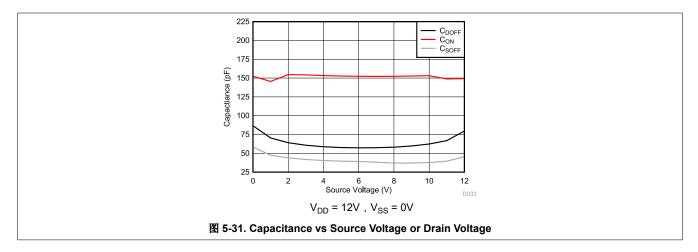


at $T_A = 25^{\circ}C$





at T_A = 25°C





6 Parameter Measurement Information

6.1 On-Resistance

The on-resistance of a device is the ohmic resistance between the source (Sx) and drain (D) pins of the device. The on-resistance varies with input voltage and supply voltage. The symbol R_{ON} is used to denote on-resistance. 6-1 shows the measurement setup used to measure R_{ON} . Voltage (V) and current (I_{SD}) are measured using the following setup, where R_{ON} is computed as $R_{ON} = V / I_{SD}$:

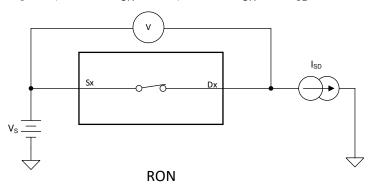


图 6-1. On-Resistance

6.2 Off-Leakage Current

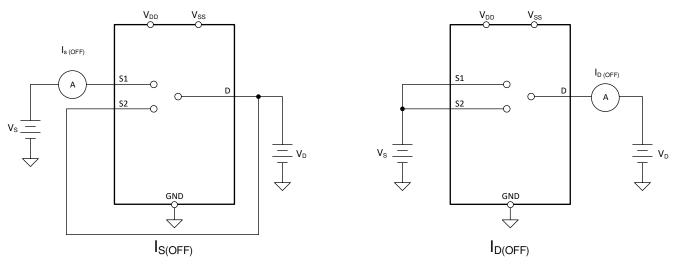
There are two types of leakage currents associated with a switch during the off state:

- 1. Source off-leakage current.
- 2. Drain off-leakage current.

Source leakage current is defined as the leakage current flowing into or out of the source pin when the switch is off. This current is denoted by the symbol $I_{S(OFF)}$.

Drain leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is off. This current is denoted by the symbol $I_{D(OFF)}$.

8 6-2 shows the setup used to measure both off-leakage currents.







6.3 On-Leakage Current

Source on-leakage current is defined as the leakage current flowing into or out of the source pin when the switch is on. This current is denoted by the symbol $I_{S(ON)}$.

Drain on-leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is on. This current is denoted by the symbol $I_{D(ON)}$.

Either the source pin or drain pin is left floating during the measurement. [4] 6-3 shows the circuit used for measuring the on-leakage current, denoted by $I_{S(ON)}$ or $I_{D(ON)}$.

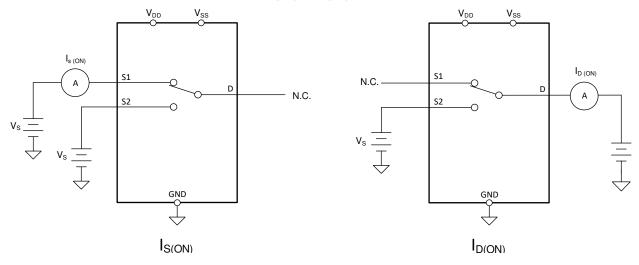


图 6-3. On-Leakage Measurement Setup

6.4 Transition Time

Transition time is defined as the time taken by the output of the device to rise or fall 90% after the address signal has risen or fallen past the logic threshold. The 90% transition measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. \mathbb{K} 6-4 shows the setup used to measure transition time, denoted by the symbol t_{TRANSITION}.

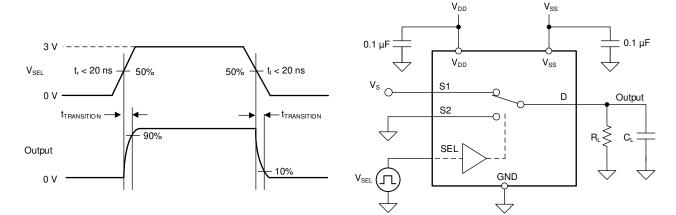


图 6-4. Transition-Time Measurement Setup



6.5 t_{ON(EN)} and t_{OFF(EN)}

Turn-on time is defined as the time taken by the output of the device to rise to 90% after the enable has risen past the logic threshold. The 90% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. \bigotimes 6-5 shows the setup used to measure turn-on time, denoted by the symbol $t_{ON(EN)}$.

Turn-off time is defined as the time taken by the output of the device to fall to 10% after the enable has fallen past the logic threshold. The 10% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. \boxtimes 6-5 shows the setup used to measure turn-off time, denoted by the symbol t_{OFF(EN)}.

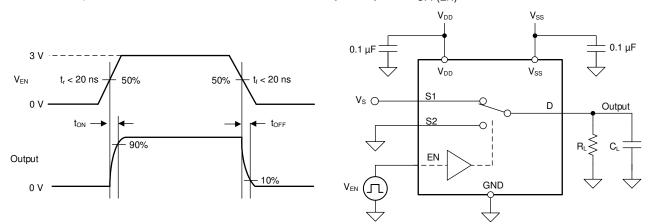


图 6-5. Turn-On and Turn-Off Time Measurement Setup

6.6 Break-Before-Make

Break-before-make delay is a safety feature that prevents two inputs from connecting when the device is switching. The output first breaks from the on-state switch before making the connection with the next on-state switch. The time delay between the *break* and the *make* is known as break-before-make delay. \boxtimes 6-6 shows the setup used to measure break-before-make delay, denoted by the symbol t_{OPEN(BBM)}.

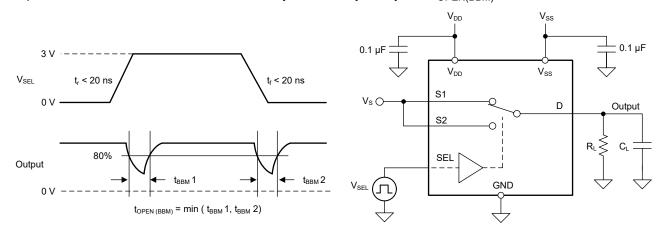


图 6-6. Break-Before-Make Delay Measurement Setup



6.7 t_{ON (VDD)} Time

The $t_{ON (VDD)}$ time is defined as the time taken by the output of the device to rise to 90% after the supply has risen past the supply threshold. The 90% measurement is used to provide the timing of the device turning on in the system. 🔀 6-7 shows the setup used to measure turn on time, denoted by the symbol $t_{ON (VDD)}$.

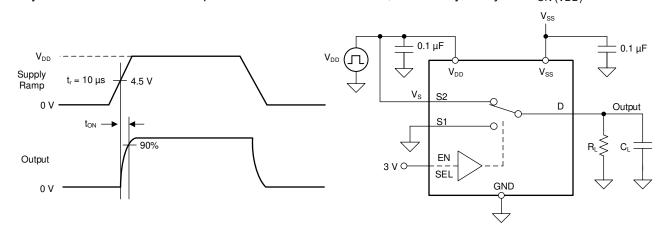


图 6-7. t_{ON (VDD)} Time Measurement Setup

6.8 Propagation Delay

Propagation delay is defined as the time taken by the output of the device to rise or fall 50% after the input signal has risen or fallen past the 50% threshold. \mathbb{E} 6-8 shows the setup used to measure propagation delay, denoted by the symbol t_{PD}.

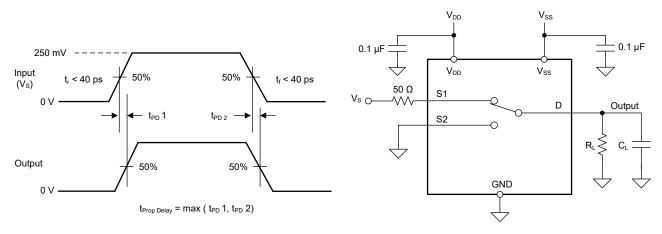


图 6-8. Propagation Delay Measurement Setup



6.9 Charge Injection

The TMUX6219-Q1 has a transmission-gate topology. Any mismatch in capacitance between the NMOS and PMOS transistors results in a charge injected into the drain or source during the falling or rising edge of the gate signal. The amount of charge injected into the source or drain of the device is known as charge injection, and is denoted by the symbol Q_{C} . \boxtimes 6-9 shows the setup used to measure charge injection from source (Sx) to drain (D).

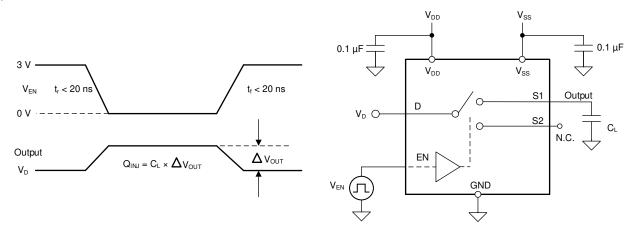


图 6-9. Charge-Injection Measurement Setup

6.10 Off Isolation

Off isolation is defined as the ratio of the signal at the drain pin (D) of the device when a signal is applied to the source pin (Sx) of an off-channel. \mathbb{E} 6-10 shows the setup used to measure, and the equation used to calculate off isolation.

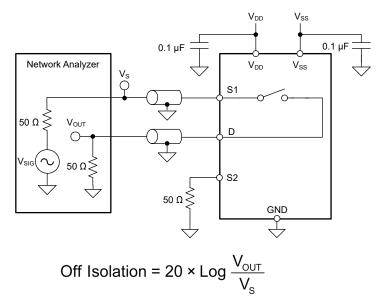


图 6-10. Off Isolation Measurement Setup



6.11 Crosstalk

Crosstalk is defined as the ratio of the signal at the drain pin (D) of a different channel, when a signal is applied at the source pin (Sx) of an on-channel. \mathbb{E} 6-11 shows the setup used to measure, and the equation used to calculate crosstalk.

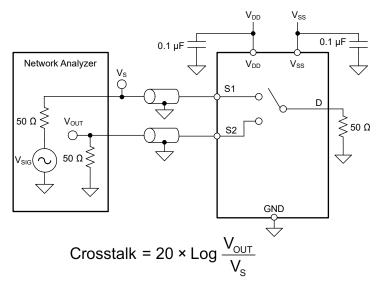


图 6-11. Crosstalk Measurement Setup

6.12 Bandwidth

Bandwidth is defined as the range of frequencies that are attenuated by less than 3 dB when the input is applied to the source pin (Sx) of an on-channel, and the output is measured at the drain pin (D) of the device. \boxtimes 6-12 shows the setup used to measure bandwidth.

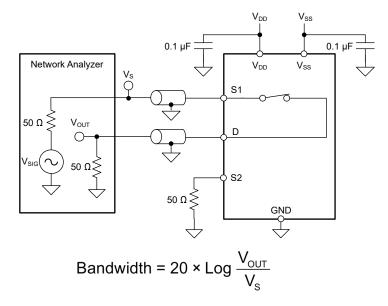


图 6-12. Bandwidth Measurement Setup



6.13 THD + Noise

The total harmonic distortion (THD) of a signal is a measurement of the harmonic distortion, and is defined as the ratio of the sum of the powers of all harmonic components to the power of the fundamental frequency at the mux output.

The on-resistance of the device varies with the amplitude of the input signal and results in distortion when the drain pin is connected to a low-impedance load. Total harmonic distortion plus noise is denoted as THD + N.

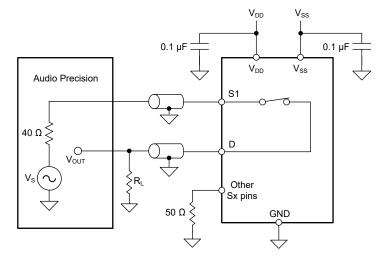


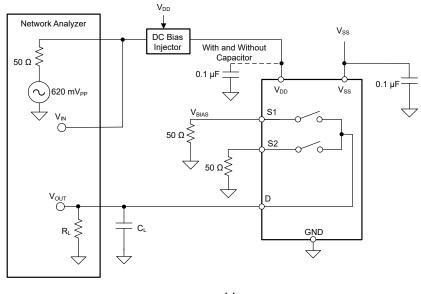
图 6-13. THD + N Measurement Setup

6.14 Power Supply Rejection Ratio (PSRR)

PSRR measures the ability of a device to prevent noise and spurious signals that appear on the supply voltage pin from coupling to the output of the switch. The DC voltage on the device supply is modulated by a sine wave of 620 mV_{PP}. The ratio of the amplitude of signal on the output to the amplitude of the modulated signal is the ACPSRR. A high ratio represents a high degree of tolerance to supply rail variation.

This helps stabilize the supply and immediately filter as much of the supply noise as possible.





 $PSRR = 20 \times Log \frac{V_{OUT}}{V_{IN}}$

图 6-14. ACPSRR Measurement Setup



7 Detailed Description

7.1 Overview

The TMUX6219-Q1 is a 2:1, 1-channel switch. Each input is turned on or turned off based on the state of the select line and enable pin.

7.2 Functional Block Diagram

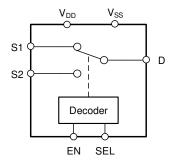


图 7-1. TMUX6219-Q1 Functional Block Diagram

7.3 Feature Description

7.3.1 Bidirectional Operation

The TMUX6219-Q1 conducts equally well from source (Sx) to drain (D) or from drain (D) to source (Sx). Each channel has very similar characteristics in both directions and supports both analog and digital signals.

7.3.2 Rail to Rail Operation

The valid signal path input or output voltage for TMUX6219-Q1 ranges from V_{SS} to V_{DD}.

7.3.3 1.8V Logic Compatible Inputs

The TMUX6219-Q1 has 1.8-V logic compatible control for all logic control inputs. 1.8-V logic level inputs allows the TMUX6219-Q1 to interface with processors that have lower logic I/O rails and eliminates the need for an external translator, which saves both space and BOM cost. For more information on 1.8V logic implementations refer to Simplifying Design with 1.8V logic Muxes and Switches.

7.3.4 Fail-Safe Logic

The TMUX6219-Q1 supports Fail-Safe Logic on the control input pins (EN and SEL) allowing for operation up to 36V above ground, regardless of the state of the supply pins. This feature allows voltages on the control pins to be applied before the supply pin, protecting the device from potential damage. Fail-Safe Logic minimizes system complexity by removing the need for power supply sequencing on the logic control pins. For example, the Fail-Safe Logic feature allows the logic input pins of the TMUX6219-Q1 to be ramped to +36V while V_{DD} and V_{SS} = 0V. The logic control inputs are protected against positive faults of up to +36V in powered-off condition, but do not offer protection against negative overvoltage conditions.



7.3.5 Latch-Up Immune

Latch-up is a condition where a low impedance path is created between a supply pin and ground. This condition is caused by a trigger (current injection or overvoltage), but once activated, the low impedance path remains even after the trigger is no longer present. This low impedance path may cause system upset or catastrophic damage due to excessive current levels. The latch-up condition typically requires a power cycle to eliminate the low impedance path.

The TMUX62xx family of devices are constructed on Silicon on Insulator (SOI) based process where an oxide layer is added between the PMOS and NMOS transistor of each CMOS switch to prevent parasitic structures from forming. The oxide layer is also known as an insulating trench and prevents triggering of latch up events due to overvoltage or current injections. The latch-up immunity feature allows the TMUX62xx family of switches and multiplexers to be used in harsh environments.

7.3.6 Ultra-Low Charge Injection

The TMUX6219-Q1 has a transmission gate topology, as shown in 🖄 7-2. Any mismatch in the stray capacitance associated with the NMOS and PMOS causes an output level change whenever the switch is opened or closed.

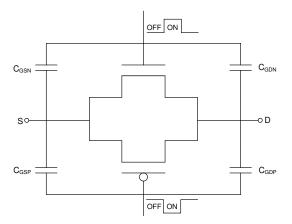


图 7-2. Transmission Gate Topology

The TMUX6219-Q1 contains specialized architecture to reduce charge injection on the source (Sx). To further reduce charge injection in a sensitive application, a compensation capacitor (Cp) can be added on the drain (D). This will ensure that excess charge from the switch transition will be pushed into the compensation capacitor on the drain (D) instead of the source (Sx). As a general rule, Cp should be $20 \times$ larger than the equivalent load capacitance on the source (Sx). As a general rule, Cp should be $20 \times$ larger than the equivalent load capacitance on the source (Sx). To further the transition variation with source voltage with different compensation capacitors on the Drain side.

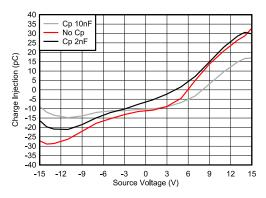


图 7-3. Charge Injection Compensation



7.4 Device Functional Modes

When the EN pin of the TMUX6219-Q1 is pulled high, one of the switches is closed based on the state of the SEL pin. When the EN pin is pulled low, both of the switches are in an open state regardless of the state of the SEL pin. The control pins can be as high as 36V.

The TMUX6219-Q1 can be operated without any external components except for the supply decoupling capacitors. The EN pin has an internal pull-up resistor of 4 M Ω and SEL pin has internal pull-down resistor of 4 M Ω . If unused, the EN pin must be tied to V_{DD} and SEL pin must be tied to GND to ensure the device does not consume additional current as highlighted in Implications of Slow or Floating CMOS Inputs. Unused signal path inputs (S1, S2, or D) should be connected to GND.

7.5 Truth Tables

7-1 provides the truth tables for the TMUX6219-Q1.

EN	SEL	Selected Source Connected To Drain (D) Pin
0	X ⁽¹⁾	All sources are off (HI-Z)
1	0	S1
1	1	S2

表 7-1. TMUX6219-Q1 Truth Table

(1) X denotes *do not care*.

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8 Application and Implementation

备注

以下应用部分中的信息不属于 TI 器件规格的范围, TI 不担保其准确性和完整性。TI 的客 户应负责确定器件是否适用于其应用。客户应验证并测试其设计,以确保系统功能。

8.1 Application Information

TMUX6219-Q1 is part of the precision switches and multiplexers family of devices. TMUX6219-Q1 offers low RON, low on and off leakage currents and ultra-low charge injection performance. These properties make TMUX6219-Q1 ideal for implementing high precision industrial systems requiring selection of one of two inputs or outputs.

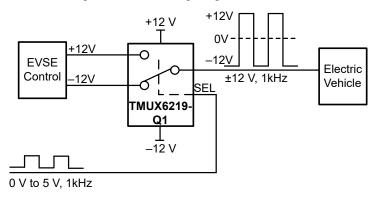
8.2 Typical Application

8.2.1 PWM Signal Generation (EV Charging Station)

One application of the TMUX6219-Q1 is in Electric Vehicle Service Equipment (EVSE). The EVSE is a system that monitors and controls the high voltage power path from the grid to the vehicle. One key feature of an EVSE is the pilot signal wire communication support that requires a 1-kHz, ±12-V PWM signal to be transmitted down the length of the charger cable to the vehicle.

The TMUX6219-Q1 can be used to generate 1kHz \pm 12V PWM signal for EVSE control pilot. A 1kHz square wave at \pm 12V generated by the EVSE on the control pilot line is used to detect the presence of the vehicle, communicate the maximum allowable charging current, and control charging.

图 8-1 shows the TMUX6219-Q1 configured for PWM signal generation for EVSE control pilot.





8.2.2 Design Requirements

For the design example, use the parameters listed in $\frac{1}{8}$ 8-1.

表 8-1. Design Parameters

PARAMETERS	VALUES				
Supply (V _{DD})	12V				
Supply (V _{SS})	-12V				
MUX I/O signal range	-12V to 12V (Rail-to-Rail)				
Control logic thresholds	1.8V compatiable (up to V _{DD})				
EN	EN pulled high to enable the switch				



8.2.3 Detailed Design Procedure

The application shown in [8] 8-1 demonstrates how to generate a ±12V PWM signal that is created by toggling the TMUX6219-Q1. This PWM signal generated by the EVSE on the control pilot line signals to the car the available current of the charger, and the car will respond with a charging status. This handshake results in a safe method for supplying power to vehicle. The TMUX6219-Q1 can support 1.8V logic signals on the control input, allowing the device to interface with low logic controls of an FPGA or MCU. The TMUX6219-Q1 can be operated without any external components except for the supply decoupling capacitors. The select pin has an internal pull-down resistor to prevent floating input logic. All inputs to the switch must fall within the recommend operating conditions of the TMUX6219-Q1 including signal range and continuous current. For this design with a positive supply of 12V on V_{DD}, and negative supply of -12V on V_{SS}, the signal range can be 12V to -12V. The max continuous current (I_{DC}) can be up to 330mA as shown in the *Recommended Operating Conditions table* for wide-range current measurement.

8.3 Power Supply Recommendations

The TMUX6219-Q1 operates across a wide supply range of of $\pm 4.5V$ to $\pm 18V$ (4.5V to 36V in single-supply mode). It also performs well with asymmetrical supplies such as V_{DD} = 8V and V_{SS} = -12V.

Power-supply bypassing improves noise margin and prevents switching noise propagation from the supply rails to other components. Good power-supply decoupling is important to achieve optimum performance. For improved supply noise immunity, use a supply decoupling capacitor ranging from 0.1 μ F to 10 μ F at both the V_{DD} and V_{SS} pins to ground. Place the bypass capacitors as close to the power supply pins of the device as possible using low-impedance connections. TI recommends using multi-layer ceramic chip capacitors (MLCCs) that offer low equivalent series resistance (ESR) and inductance (ESL) characteristics for power-supply decoupling purposes. For very sensitive systems, or for systems in harsh noise environments, avoiding the use of vias for connecting the capacitors to the device pins may offer superior noise immunity. The use of multiple vias in parallel lowers the overall inductance and is beneficial for connections to power and ground planes. Always ensure the ground (GND) connection is established before supplies are ramped.

8.4 Layout

8.4.1 Layout Guidelines

When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self – inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners. 🕅 8-2 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

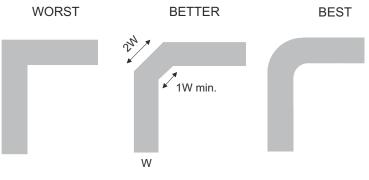


图 8-2. Trace Example

Route high-speed signals using a minimum of vias and corners which reduces signal reflections and impedance changes. When a via must be used, increase the clearance size around it to minimize its capacitance. Each via introduces discontinuities in the signal's transmission line and increases the chance of picking up interference



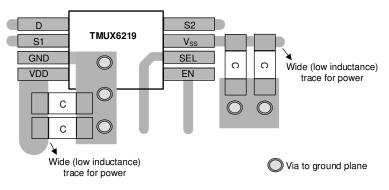


from the other layers of the board. Be careful when designing test points, through-hole pins are not recommended at high frequencies.

8-3 shows an example of a PCB layout with the TMUX6219-Q1. Some key considerations are as follows:

- Decouple the supply pins with a 0.1µF and 1µF capacitor, and place the lowest value capacitor as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient for the supply voltage.
- Keep the input lines as short as possible.
- Use a solid ground plane to help reduce electromagnetic interference (EMI) noise pickup.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible, and only make perpendicular crossings when necessary.
- Using multiple vias in parallel will lower the overall inductance and is beneficial for connection to ground planes.

8.4.2 Layout Example







9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation

For related documentation, see the following:

- · Texas Instruments, Improve Stability Issues with Low CON Multiplexers application brief
- · Texas Instruments, Improving Signal Measurement Accuracy in Automated Test Equipment application brief
- Texas Instruments, Multiplexers and Signal Switches Glossary application report
- Texas Instruments, QFN/SON PCB Attachment application report
- Texas Instruments, Quad Flatpack No-Lead Logic Packages application report
- Texas Instruments, Simplifying Design with 1.8V logic Muxes and Switches application brief
- Texas Instruments, System-Level Protection for High-Voltage Analog Multiplexers application report
- Texas Instruments, TMUX6219-Q1 Functional Safety, FIT Rate, Failure Mode Distribution and Pin FMA functional safety FIT rate, FMD and Pin-FMA

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 支持资源

TI E2E[™] 中文支持论坛是工程师的重要参考资料,可直接从专家处获得快速、经过验证的解答和设计帮助。搜索现有解答或提出自己的问题,获得所需的快速设计帮助。

链接的内容由各个贡献者"按原样"提供。这些内容并不构成 TI 技术规范,并且不一定反映 TI 的观点;请参阅 TI 的使用条款。

9.4 Trademarks

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9.5 静电放电警告



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ESD 的损坏小至导致微小的性能降级,大至整个器件故障。精密的集成电路可能更容易受到损坏,这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

9.6 术语表

TI术语表 本术语表列出并解释了术语、首字母缩略词和定义。

10 Revision History

注:以前版本的页码可能与当前版本的页码不同

С	hanges from Revision B (July 2024) to Revision C (December 2024)	Page
•	删除了整个数据表中所有提及 RQX 封装的地方	1

Changes from Revision A (June 2021) to Revision B (July 2024) Pa				
Changed IIH max specification	6			



Changes from Revision * (January 2021) to Revision A (June 2021) Page

• 将文档状态从预告信息更改为量产数据......1

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
TMUX6219DGKRQ1	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	(X219, X219Q) Q
TMUX6219DGKRQ1.B	Active	Production	VSSOP (DGK) 8	2500 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	(X219, X219Q) Q

⁽¹⁾ **Status:** For more details on status, see our product life cycle.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

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OTHER QUALIFIED VERSIONS OF TMUX6219-Q1 :



www.ti.com

• Catalog : TMUX6219

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product



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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal	
	r

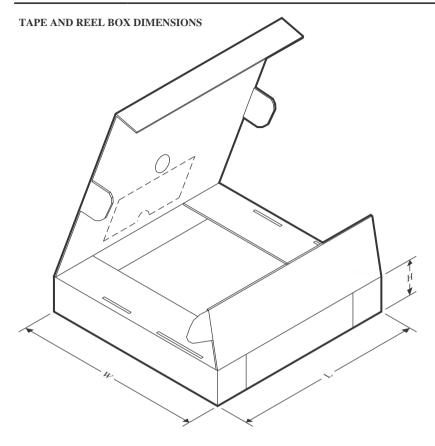
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TMUX6219DGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1



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PACKAGE MATERIALS INFORMATION

18-Jul-2025



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TMUX6219DGKRQ1	VSSOP	DGK	8	2500	353.0	353.0	32.0

DGK0008A



PACKAGE OUTLINE

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



NOTES:

PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-187.



DGK0008A

EXAMPLE BOARD LAYOUT

[™] VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown
- on this view. It is recommended that vias under paste be filled, plugged or tented.
- 9. Size of metal pad may vary due to creepage requirement.



DGK0008A

EXAMPLE STENCIL DESIGN

[™] VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

12. Board assembly site may have different recommendations for stencil design.



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